WEST

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Term:

```
l15 and (compress$4 or compact$4)  same (pull$1up
or pull$1down)same latch$4 same (ic or (integrat$3
near2         circuit$3)  or semi$1conduct$7 or
memor$7) and (clock or timing)same (test$3 or
```

Display: `20` **Documents in** <u>Display Format</u>: `-` **Starting with Number** `1`

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Search History

DATE: Monday, September 30, 2002   <u>Printable Copy</u>   <u>Create Case</u>

<u>Set Name</u> side by side	<u>Query</u>	<u>Hit Count</u>	<u>Set Name</u> result set
DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ			
<u>L18</u>	l15 and l16	4	<u>L18</u>
<u>L17</u>	l15 and (compress$4 or compact$4) same (pull$1up or pull$1down)same latch$4 same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7) and (clock or timing)same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4)	4	<u>L17</u>
<u>L16</u>	l14 and (compress$4 or compact$4) same (pull$1up or pull$1down)same latch$4 same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7) and (clock or timing)same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4)	4	<u>L16</u>
<u>L15</u>	l14 and (compress$4 or compact$4) and (pull$1up or pull$1down)same latch$4 same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7) and (clock or timing)same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4)	43	<u>L15</u>

L14	l13 and (compress$4 or compact$4) and (pull$1up or pull$1down)same latch$4 same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7) and (clock or timing)	115	L14
L13	(compress$4 or compact$4) and (pull$1up or pull$1down)same latch$4	498	L13
L12	l1 and (pull$1up or pull$1down)same latch$4	1	L12
L11	l7 and (pull$1up or pull$1down)same latch$4	1	L11
L10	(pull$1up or pull$1down)same latch$4	2589	L10
L9	('6163491')[ABPN1,NRPN,PN,TBAN,WKU]	2	L9
L8	l7 and double data rate same (compress$4 or compact$4) same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4) same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7) and (clock or timing)	1	L8
L7	l6 and double data rate and (compress$4 or compact$4) same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4) same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7) and (clock or timing)	11	L7
L6	double data rate and (compress$4 or compact$4) same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4) same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7)	12	L6
L5	l1 and (double near (data or rate) or ddr)same (compress$4 or compact$4) same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4) and (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7)	11	L5
L4	('6324602')[ABPN1,NRPN,PN,TBAN,WKU]	2	L4
L3	('6317372')[ABPN1,NRPN,PN,TBAN,WKU]	2	L3
L2	l1 and (double near (data or rate) or ddr)same (compress$4 or compact$4) same (test$3 or debug$4 or verif$7 or diagno$5 or probing or probe or exerci$4) same (ic or (integrat$3 near2 circuit$3) or semi$1conduct$7 or memor$7)	3	L2
L1	(double near (data or rate) or ddr)same (compress$4 or compact$4)	163	L1

END OF SEARCH HISTORY